

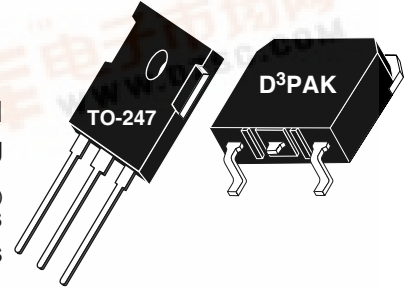


# APT1001R6BFLL APT1001R6SFLL

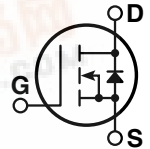
1000V 8A 1.60Ω

## POWER MOS 7<sup>®</sup> FREDFET

Power MOS 7<sup>®</sup> is a new generation of low loss, high voltage, N-Channel enhancement mode power MOSFETS. Both conduction and switching losses are addressed with Power MOS 7<sup>®</sup> by significantly lowering  $R_{DS(ON)}$  and  $Q_g$ . Power MOS 7<sup>®</sup> combines lower conduction and switching losses along with exceptionally fast switching speeds inherent with APT's patented metal gate structure.



- Lower Input Capacitance
- Lower Miller Capacitance
- Lower Gate Charge,  $Q_g$
- Increased Power Dissipation
- Easier To Drive
- TO-247 or Surface Mount D<sup>3</sup>PAK Package
- **FAST RECOVERY BODY DIODE**



### MAXIMUM RATINGS

All Ratings:  $T_C = 25^\circ\text{C}$  unless otherwise specified.

Symbol	Parameter	APT1001R6BFLL_SFLL	UNIT
$V_{DSS}$	Drain-Source Voltage	1000	Volts
$I_D$	Continuous Drain Current @ $T_C = 25^\circ\text{C}$	8	Amps
$I_{DM}$	Pulsed Drain Current <sup>①</sup>	32	
$V_{GS}$	Gate-Source Voltage Continuous	±30	Volts
$V_{GSM}$	Gate-Source Voltage Transient	±40	
$P_D$	Total Power Dissipation @ $T_C = 25^\circ\text{C}$	266	Watts
	Linear Derating Factor	2.13	W/°C
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to 150	°C
$T_L$	Lead Temperature: 0.063" from Case for 10 Sec.	300	
$I_{AR}$	Avalanche Current <sup>①</sup> (Repetitive and Non-Repetitive)	4	Amps
$E_{AR}$	Repetitive Avalanche Energy <sup>①</sup>	16	mJ
$E_{AS}$	Single Pulse Avalanche Energy <sup>④</sup>	425	

### STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-Source Breakdown Voltage ( $V_{GS} = 0V, I_D = 250\mu A$ )	1000			Volts
$R_{DS(on)}$	Drain-Source On-State Resistance <sup>②</sup> ( $V_{GS} = 10V, I_D = 4A$ )			1.600	Ohms
$I_{DSS}$	Zero Gate Voltage Drain Current ( $V_{DS} = 1000V, V_{GS} = 0V$ )			250	$\mu A$
	Zero Gate Voltage Drain Current ( $V_{DS} = 800V, V_{GS} = 0V, T_C = 125^\circ\text{C}$ )			1000	
$I_{GSS}$	Gate-Source Leakage Current ( $V_{GS} = \pm 30V, V_{DS} = 0V$ )			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage ( $V_{DS} = V_{GS}, I_D = 1mA$ )	3		5	Volts

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

**DYNAMIC CHARACTERISTICS**

APT1001R6BFL SFL

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1\text{ MHz}$		1320		pF
$C_{oss}$	Output Capacitance			230		
$C_{rss}$	Reverse Transfer Capacitance			42		
$Q_g$	Total Gate Charge ③	$V_{GS} = 10V$ $V_{DD} = 500V$ $I_D = 8A @ 25^\circ C$		55		nC
$Q_{gs}$	Gate-Source Charge			7		
$Q_{gd}$	Gate-Drain ("Miller") Charge			35		
$t_{d(on)}$	Turn-on Delay Time	<b>RESISTIVE SWITCHING</b> $V_{GS} = 15V$ $V_{DD} = 500V$ $I_D = 8A @ 25^\circ C$ $R_G = 0.6\Omega$		18		ns
$t_r$	Rise Time			18		
$t_{d(off)}$	Turn-off Delay Time			32		
$t_f$	Fall Time			19		
$E_{on}$	Turn-on Switching Energy ⑥	<b>INDUCTIVE SWITCHING @ 25°C</b> $V_{DD} = 667V$ $V_{GS} = 15V$ $I_D = 8A$ , $R_G = 5\Omega$		210		$\mu J$
$E_{off}$	Turn-off Switching Energy			40		
$E_{on}$	Turn-on Switching Energy ⑥	<b>INDUCTIVE SWITCHING @ 125°C</b> $V_{DD} = 667V$ $V_{GS} = 15V$ $I_D = 8A$ , $R_G = 5\Omega$		450		
$E_{off}$	Turn-off Switching Energy			50		

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS**

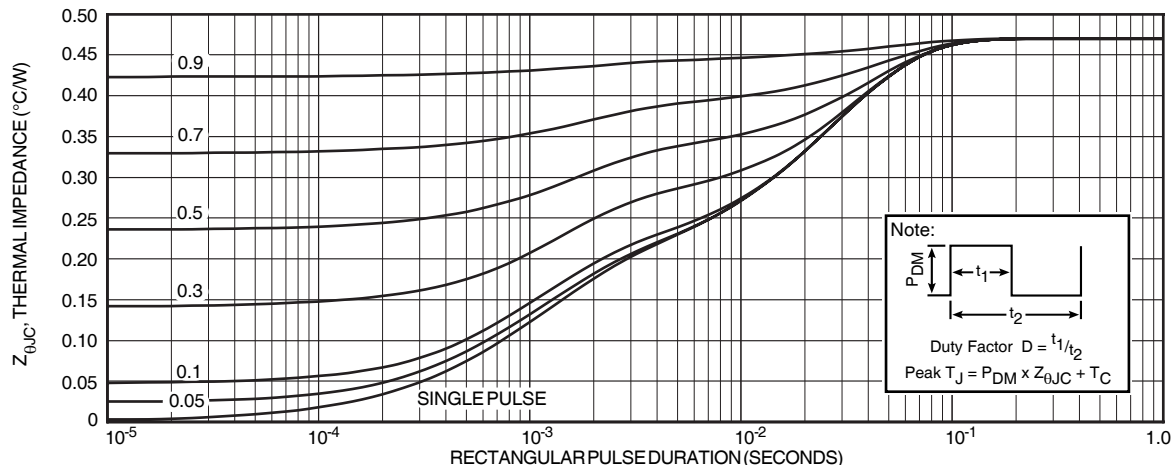
Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$I_S$	Continuous Source Current (Body Diode)			8	Amps
$I_{SM}$	Pulsed Source Current ① (Body Diode)			32	
$V_{SD}$	Diode Forward Voltage ② ( $V_{GS} = 0V$ , $I_S = -8A$ )			1.3	Volts
$dv/dt$	Peak Diode Recovery $dv/dt$ ⑤			18	V/ns
$t_{rr}$	Reverse Recovery Time ( $I_S = -8A$ , $di/dt = 100A/\mu s$ )	$T_j = 25^\circ C$		250	ns
		$T_j = 125^\circ C$		515	
$Q_{rr}$	Reverse Recovery Charge ( $I_S = -8A$ , $di/dt = 100A/\mu s$ )	$T_j = 25^\circ C$		0.50	$\mu C$
		$T_j = 125^\circ C$		1.1	
$I_{RRM}$	Peak Recovery Current ( $I_S = -8A$ , $di/dt = 100A/\mu s$ )	$T_j = 25^\circ C$		8.3	Amps
		$T_j = 125^\circ C$		11.5	

**THERMAL CHARACTERISTICS**

Symbol	Characteristic	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction to Case			0.47	$^\circ C/W$
$R_{\theta JA}$	Junction to Ambient			40	

- ① Repetitive Rating: Pulse width limited by maximum junction temperature
- ② Pulse Test: Pulse width < 380  $\mu s$ , Duty Cycle < 2%
- ③ See MIL-STD-750 Method 3471
- ④ Starting  $T_j = +25^\circ C$ ,  $L = 13.28mH$ ,  $R_G = 25\Omega$ , Peak  $I_L = 8A$
- ⑤  $dv/dt$  numbers reflect the limitations of the test circuit rather than the device itself.  $I_S \leq I_D - 8A$   $di/dt \leq 700A/\mu s$   $V_F \leq 1000$   $T_j \leq 150^\circ C$
- ⑥  $E_{on}$  includes diode reverse recovery. See figures 18, 20.

APT Reserves the right to change, without notice, the specifications and information contained herein.



# Typical Performance Curves

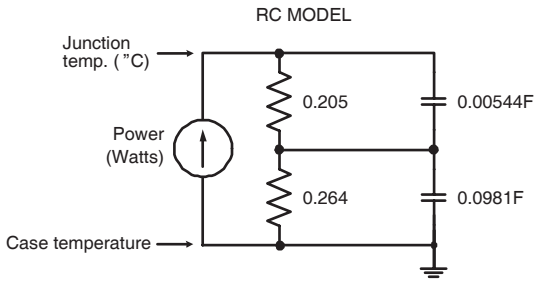


FIGURE 2, TRANSIENT THERMAL IMPEDANCE MODEL

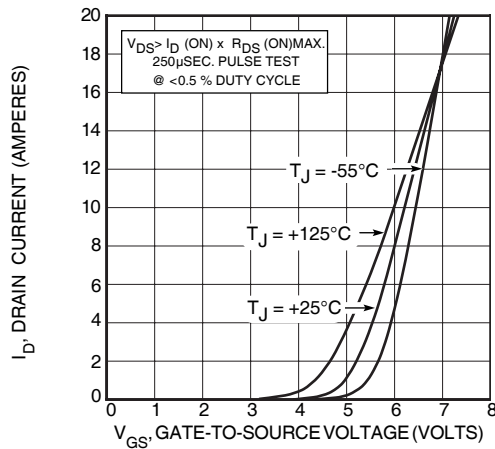


FIGURE 4, TRANSFER CHARACTERISTICS

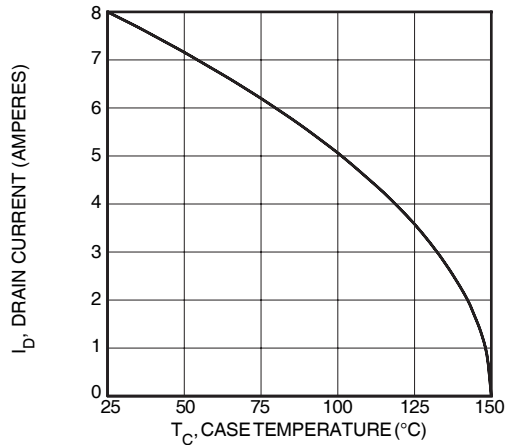


FIGURE 6, MAXIMUM DRAIN CURRENT vs CASE TEMPERATURE

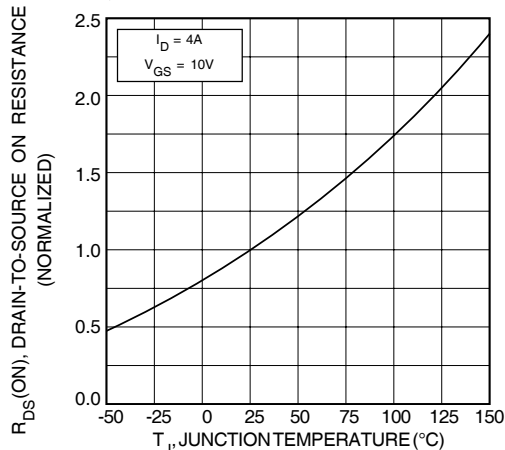


FIGURE 8, ON-RESISTANCE vs. TEMPERATURE

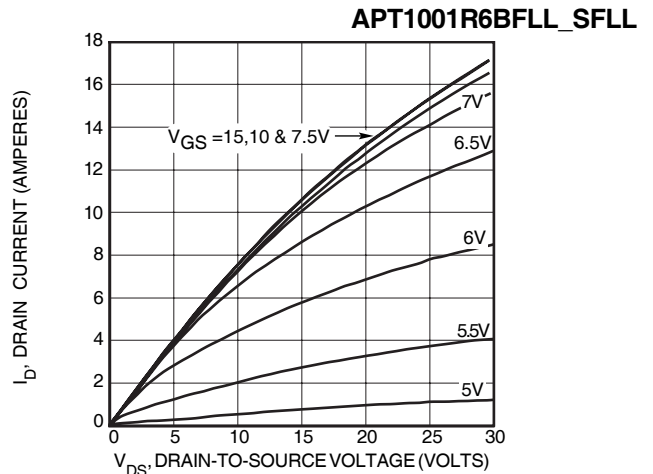


FIGURE 3, LOW VOLTAGE OUTPUT CHARACTERISTICS

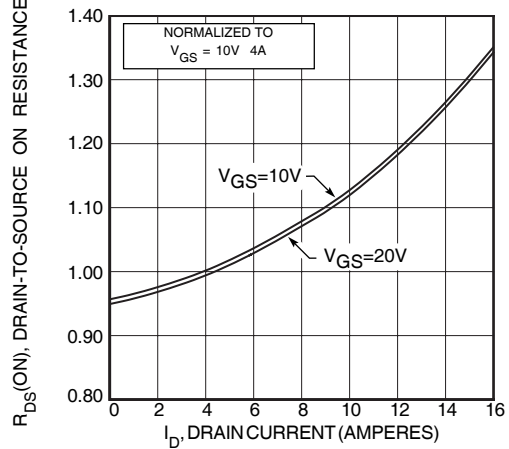


FIGURE 5,  $R_{DS}(\text{ON})$  vs DRAIN CURRENT

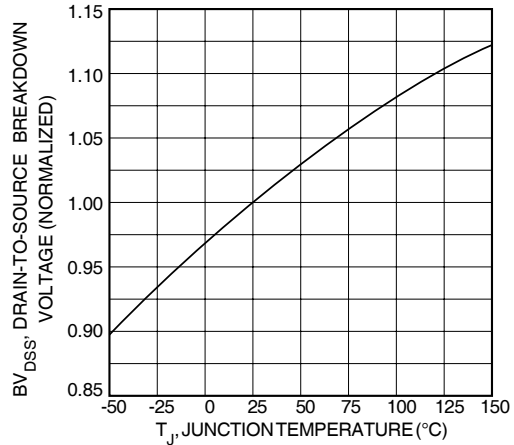


FIGURE 7, BREAKDOWN VOLTAGE vs TEMPERATURE

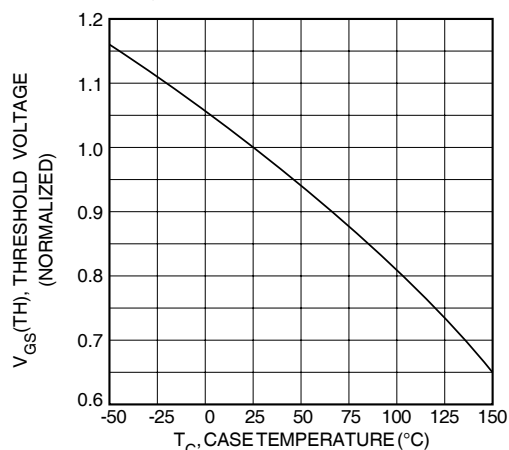


FIGURE 9, THRESHOLD VOLTAGE vs TEMPERATURE

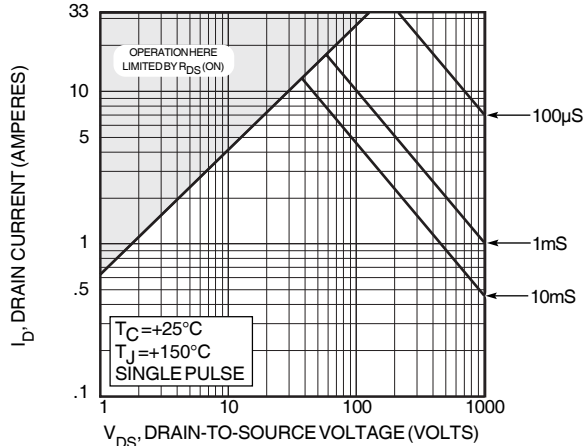


FIGURE 10, MAXIMUM SAFE OPERATING AREA

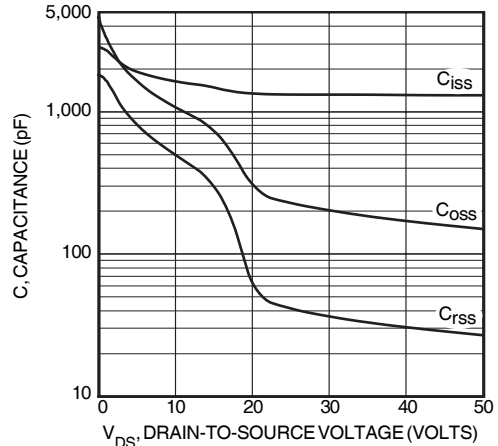


FIGURE 11, CAPACITANCE vs DRAIN-TO-SOURCE VOLTAGE

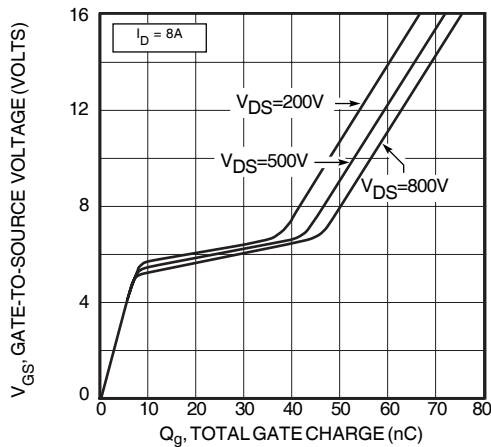


FIGURE 12, GATE CHARGE vs GATE-TO-SOURCE VOLTAGE

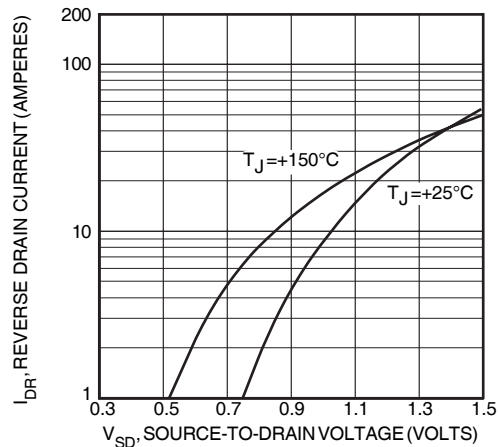


FIGURE 13, SOURCE-DRAIN DIODE FORWARD VOLTAGE

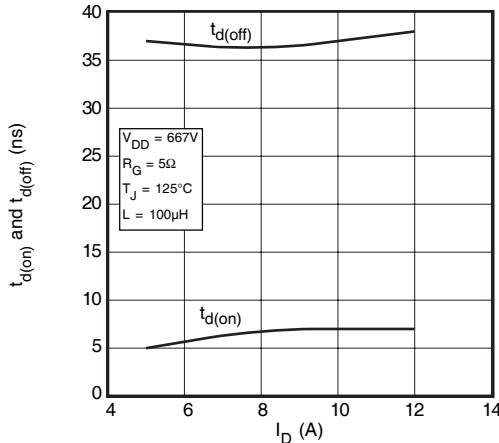


FIGURE 14, DELAY TIMES vs CURRENT

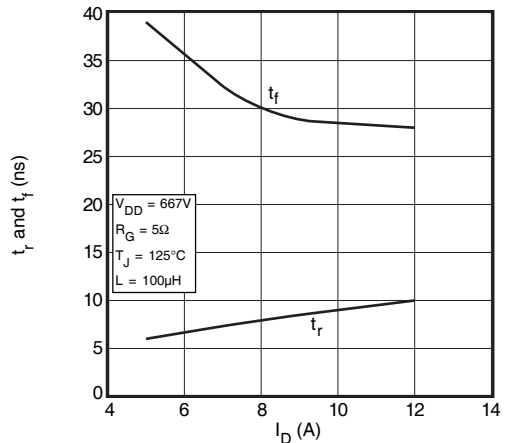


FIGURE 15, RISE AND FALL TIMES vs CURRENT

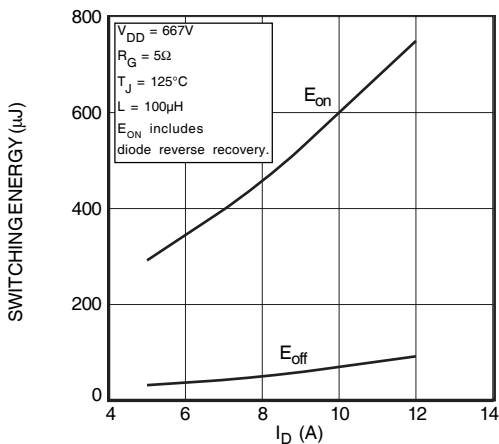


FIGURE 16, SWITCHING ENERGY vs CURRENT

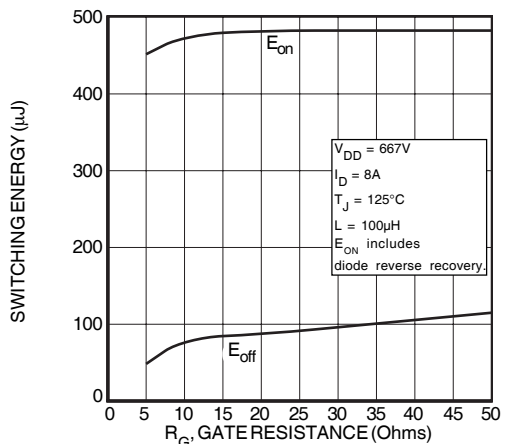


FIGURE 17, SWITCHING ENERGY vs. GATE RESISTANCE

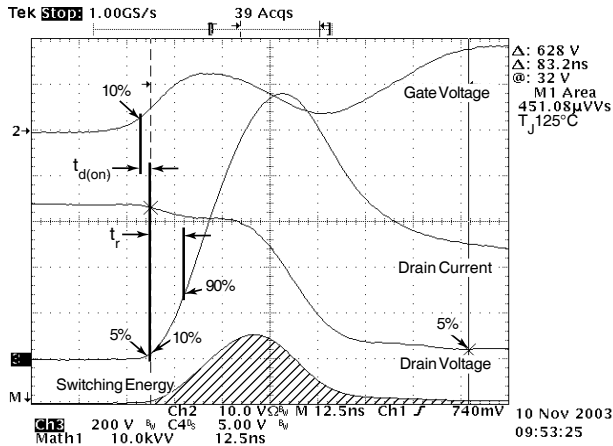


Figure 18, Turn-on Switching Waveforms and Definitions

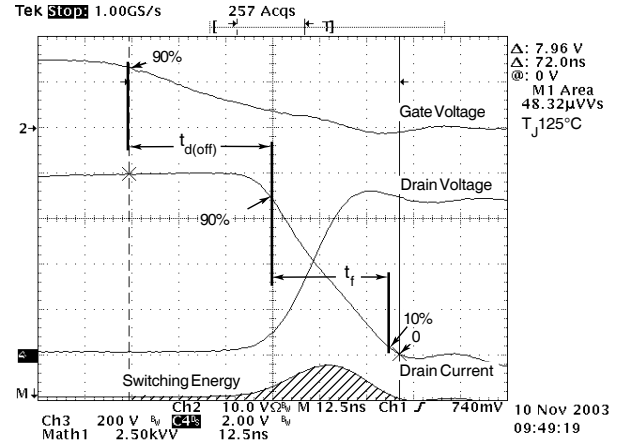


Figure 19, Turn-off Switching Waveforms and Definitions

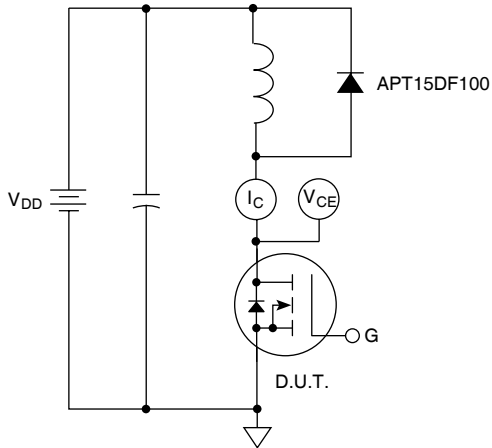
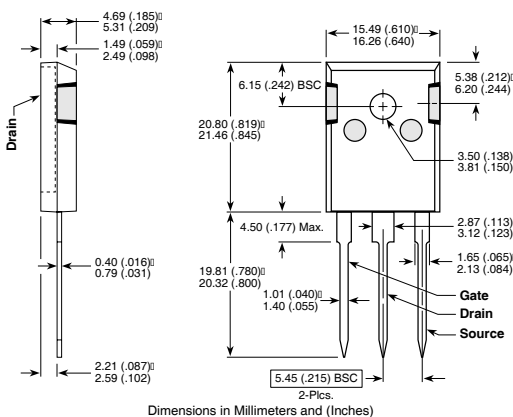


Figure 20, Inductive Switching Test Circuit

TO-247 Package Outline



D<sup>3</sup>PAK Package Outline

